


<b>Search Notes</b>  	<b>Application/Control No.</b>  10518072	<b>Applicant(s)/Patent Under Reexamination</b>  WEILL ET AL.
	<b>Examiner</b>  NASHAAT T NASHED	<b>Art Unit</b>  1656

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
SEQ ID NO: 1 search in Comm. databases, PGPub, issued patent.	2/5/10	nash
STN Search	2/6/10	nash
West Search	2/6/10	nash

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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